

Notice of References Cited	Application/Control No. 10/604,176		Applicant(s)/Patent Under Reexamination VOLDMAN, STEVEN H.	
	Examiner Zeev Kitov		Art Unit 2836	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Haseloff, Latch-Up, ESD and Other Phenomena, Application Report, Texas Instrument SLYA014A, May 2000, http://www.ti.com , pp. 1 - 8.
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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